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#### 1 Capacity of text marking channel

Low, S.H.; Maxemchuk, N.F.;

Signal Processing Letters, IEEE , Volume: 7 , Issue: 12 , Dec. 2000

Pages: 345 - 347

[Abstract] [PDF Full-Text (56 KB)]

#### 2 A robust oblivious watermarking scheme

Ramkumar, M.; Akansu, A.N.;

Image Processing, 2000. Proceedings. 2000 International Conference on , Vo 2 , 10-13 Sept. 2000

Pages: 61 - 64 vol. 2

[Abstract] [PDF Full-Text (352 KB)]

#### 3 Image watermarking with zero-mean patches

Ratnakar, V.;

Signals, Systems, and Computers, 1999. Conference Record of the Thirty-Thi Asilomar Conference on , Volume: 2 , 24-27 Oct. 1999

Pages:1513 - 1517 vol.2

[Abstract] [PDF Full-Text (560 KB)]

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O- Access the IEEE Member	[Abstract] [PDF Full-Text (1184KB)] IEEE JNL
Digital Library	3 A 500-MHz pipelined burst SRAM with improved SER immunity Sato, H.; Wada, T.; Ohbayashi, S.; Kozaru, K.; Okamoto, Y.; Higashide, Y.; Shimizu, T.; Maki, Y.; Morimoto, R.; Otoi, H.; Koga, T.; Honda, H.; Taniguchi Arita, Y.; Shiomi, T.; Solid-State Circuits, IEEE Journal of ,Volume: 34 , Issue: 11 , Nov. 1999 Pages:1571 - 1579
	[Abstract] [PDF Full-Text (548KB)] IEEE JNL
	4 A 5-MHz, 3.6-mW, 1.4-V SRAM with nonboosted, vertical bipolar bit contact memory cell Sato, H.; Nagaoka, H.; Honda, H.; Maki, Y.; Wada, T.; Arita, Y.; Tsutsumi, K. Taniguchi, M.; Yamada, M.; Solid-State Circuits, IEEE Journal of ,Volume: 33 , Issue: 11 , Nov. 1998 Pages:1672 - 1681  [Abstract] [PDF Full-Text (220KB)] IEEE JNL

5 Basic study on the application of parametric spline functions to the

#### holographic pattern measuring system

Taniguchi, M.; Tsuchiya, T.; Takagi, T.;

Instrumentation and Measurement, IEEE Transactions on ,Volume: 47 , Issue

1, Feb. 1998 Pages: 153 - 157

[Abstract] [PDF Full-Text (148KB)] IEEE JNL

# 6 Holographic pattern measuring system and its application to deformation analysis of printed circuit board due to heat of mounted

Taniguchi, M.; Takagi, T.;

Instrumentation and Measurement, IEEE Transactions on ,Volume: 43, Issue 2 , Apr 1994

Pages: 326 - 331

[Abstract] [PDF Full-Text (596KB)] IEEE JNL

# 7 The feature of the narrow-pulse transmission on conventional copia waveguides when power leakage is present

Tsuji, M.; Taniguchi, M.; Shigesawa, H.;

Microwave Theory and Techniques, IEEE Transactions on ,Volume: 41 , Issue

6 , June-July 1993 Pages: 1017 - 1023

[Abstract] [PDF Full-Text (660KB)] IEEE JNL

# 8 A holographic measurement of microscopical sliding of electrical co due to contact spring thermal deformation

Taniguchi, M.; Sone, H.; Takagi, T.;

Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [ also IEEE Trans. on Components, Packaging, and Manufacturing Technology, A, B, C] , Volume: 13 , Issue: 1 , March 1990

Pages: 20 - 26

[Abstract] [PDF Full-Text (700KB)] IEEE JNL

#### 9 Videotex: advancing to higher bandwidth

Sugimoto, M.; Taniguchi, M.; Yokoi, S.; Hata, H.;

Communications Magazine, IEEE ,Volume: 26 , Issue: 2 , Feb. 1988

Pages:22 - 30

[Abstract] [PDF Full-Text (676KB)] IEEE JNL

## 10 Physiological, clinical and psychological applications of dynamic infrared imaging

Anbar, M.;

Engineering in Medicine and Biology Society, 2003. Proceedings of the 25th A International Conference of the IEEE ,Volume: 2, 17-21 Sept. 2003 Pages:1121 - 1124

[Abstract] [PDF Full-Text (370KB)] IEEE CNF

11 An effective electrical isolation scheme by iron implantation at diff

#### substrate temperatures

Too, P.; Ahmed, S.; Sealy, B.J.; Gwilliam, R.; Ion Implantation Technology. 2002. Proceedings of the 14th International Conference on , 22-27 Sept. 2002 Pages:610 - 613

[Abstract] [PDF Full-Text (324KB)] IEEE CNF

### 12 An experimental study on the relationships between the speckle n and the deformation of optical fiber

Taniguchi, M.; Hasegawa, M.; Takagi, T.;

SICE 2002. Proceedings of the 41st SICE Annual Conference , Volume: 5 , 5-2002

Pages: 2967 - 2971 vol.5

[Abstract] [PDF Full-Text (352KB)] IEEE CNF

### 13 A theoretical approach to analysis on the downstream and upstrea road traffic flow rate of a single intersection

Takagi, T.; Taniguchi, M.; Fujiki, S.; Kamimura, S.; Suzuki, N.;

SICE 2002. Proceedings of the 41st SICE Annual Conference , Volume: 5 , 5-

Pages: 2873 - 2878 vol. 5

[Abstract] [PDF Full-Text (306KB)] IEEE CNF

# 14 Application of holographic interferometry measuring technique to deformation measurement of bone due to thermal stress

Kozuchi, J.; Taniguchi, M.; Chubachi, N.; Takagi, T.; Instrumentation and Measurement Technology Conference, 2002. IMTC/2002 Proceedings of the 19th IEEE ,Volume: 1 , 21-23 May 2002 Pages: 369 - 374 vol.1

[Abstract] [PDF Full-Text (853KB)] IEEE CNF

15 Fabrication of flat electrodes with nano-gaps using cluster ion bea Taniguchi, M.; Kawai, T.; Watanabe, K.; Matsui, S.; Toyoda, N.; Yamada, I.; Kubota, T.; Mashik, S.;

Microprocesses and Nanotechnology Conference, 2002. Digest of Papers. Microprocesses and Nanotechnology 2002. 2002 International, 6-8 Nov. 200. Pages: 152 - 153

[Abstract] [PDF Full-Text (171KB)] IEEE CNF

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18 Failure diagnosis method for machinery in unsteady operating condition by instantaneous power spectrum and genetic programming

Peng Chen; Toyota, T.; Taniguchi, M.; Fang Feng; Hiho, T.;

Knowledge-Based Intelligent Engineering Systems and Allied Technologies, 20 Proceedings. Fourth International Conference on ,Volume: 2 , 30 Aug.-1 Sep 2000

Pages:640 - 643 vol.2

[Abstract] [PDF Full-Text (272KB)] IEEE CNF

19 Extraction of feature spectra by instantaneous power spectrum an automatic generation of symptom parameters by GP for diagnosis of machinery in unsteady operating condition

Taniguchi, M.; Peng Chen; Toyota, T.;

Industrial Electronics Society, 2000. IECON 2000. 26th Annual Confjerence of

IEEE ,Volume: 3 , 22-28 Oct. 2000

Pages:1696 - 1700 vol.3



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Tables of Contents	_				
O- Journals & Magazines	Results Key:  JNL = Journal or Magazine CNF = Conference STD = Standard				
Conference Proceedings Standards	Industrial applications of short-term prediction on chaotic time se by local fuzzy reconstruction method  Iokibe, T.; Koyama, M.; Taniguchi, M.;  Knowledge-Based Intelligent Electronic Systems, 1997. KES '97. Proceedings.				
O- By Author	1997 First International Conference on ,Volume: 1 , 21-23 May 1997 Pages: 126 - 130 vol.1				
O- Basic O- Advanced	[Abstract] [PDF Full-Text (428KB)] IEEE CNF				
Member Services  - Join IEEE - Establish IEEE Web Account - Access the	Optical adaptive processing for an intensity invariant pattern recognition  Matsuoka, K.; Taniguchi, M.; Mokuno, Y.;  Lasers and Electro-Optics, 1995. Technical Digest. CLEO/Pacific Rim'95., Pacif Rim Conference on , 10-14 July 1995  Pages: 290				
IEEE Member Digital Library	[Abstract] [PDF Full-Text (132KB)] IEEE CNF				
	Use of limited distortion invariant correlation filters for recognition road signs  Taniguchi, M.; Matsuoka, K.;  Lasers and Electro-Optics, 1995. Technical Digest. CLEO/Pacific Rim'95., Pacif Rim Conference on , 10-14 July 1995  Pages: 290				
	[Abstract] [PDF Full-Text (240KB)] IEEE CNF				
	A new structure of field emitter arrays  Itoh, S.; Niiyama, T.; Taniguchi, M.; Watanabe, T.;  Vacuum Microelectronics Conference, 1995. IVMC., 1995 International, 30 Ju  Aug. 1995  Pages:99 - 102				
	[Abstract] [PDF Full-Text (224KB)] IEEE CNF				

35 Thermal deformation measurement and evaluation of printed circu

#### board by using holography

Taniguchi, M.; Takagi, T.;

Instrumentation and Measurement Technology Conference, 1994. IMTC/94. Conference Proceedings. 10th Anniversary. Advanced Technologies in I & M., IEEE , 10-12 May 1994

Pages:1527 - 1528 vol.3

[Abstract] [PDF Full-Text (168KB)] IEEE CNF

### 36 An experimental study on the application of stroboscopic holograp impulsive vibration analysis of printed circuit board

Taniguchi, M.; Takagi, T.; Akasaki, I.;

Instrumentation and Measurement Technology Conference, 1994. IMTC/94. Conference Proceedings. 10th Anniversary. Advanced Technologies in I & M., IEEE , 10-12 May 1994

Pages: 204 - 207 vol. 1

[Abstract] [PDF Full-Text (356KB)] IEEE CNF

### 37 A study on efficiency of the driver information system in the Tokyc Metropolitan area

Hato, E.; Taniguchi, M.;

Vehicle Navigation and Information Systems Conference, 1994. Proceedings., 1994, 31 Aug.-2 Sept. 1994

Pages:401 - 404

[Abstract] [PDF Full-Text (244KB)] IEEE CNF

### 38 Comparison Of Different Neural Approximation Approaches In The **Tracking Problem**

Taniguchi, M.; Lang, M.;

Neural Networks, 1993. IJCNN '93-Nagoya. Proceedings of 1993 Internationa

Conference on ,Volume: 2 , October 25-29, 1993

Pages: 1743 - 1746

[Abstract] [PDF Full-Text (348KB)] IEEE CNF

## 39 Driving control system for an autonomous vehicle using multiple observed point information

Hattori, A.; Hosaka, A.; Taniguchi, M.; Nakano, E.;

Intelligent Vehicles '92 Symposium., Proceedings of the , 29 June-1 July 1992 Pages: 207 - 212

[Abstract] [PDF Full-Text (488KB)] IEEE CNF

### 40 Basic study on possibility for application of optical fiber to the interferometry

Taniguchi, M.; Oki, M.; Takagi, T.;

Instrumentation and Measurement Technology Conference, 1991. IMTC-91.

Conference Record., 8th IEEE, 14-16 May 1991

Pages:135 - 137

[Abstract] [PDF Full-Text (252KB)] IEEE CNF

#### 41 Enhanced reliability of HEMT by using a TiN barrier

Taniguchi, M.; Amano, Y.; Nemoto, T.; Shinohara, K.; Reliability Physics Symposium, 1990. 28th Annual Proceedings., International 29 March 1990 Pages:94 - 98

[Abstract] [PDF Full-Text (252KB)] IEEE CNF

# 42 A holographic measurement of microscopical sliding of electrical contact due to contact spring thermal deformation

Taniguchi, M.; Sone, H.; Takagi, T.; Electrical Contacts, 1989., Proceedings of the Thirty Fifth Meeting of the IEEE Conference on , 18-20 Sept. 1989

Pages: 245 - 252

[Abstract] [PDF Full-Text (824KB)] IEEE CNF

### 43 Holographic pattern testing of printed circuit board (PCB) deforma due to thermal stress

Taniguchi, M.; Takagi, T.; Electronic Manufacturing Technology Symposium, 1989, Proceedings. Japan I Symposium, Sixth IEEE/CHMT International, 26-28 April 1989 Pages: 272 - 275

[Abstract] [PDF Full-Text (412KB)] IEEE CNF

# 44 A Holographic Pattern Measuring System (HPMS) and Its Applicati the Thermal Deformation of an Electrical Contact Spring

Taniguchi, M.; Oki, M.; Takagi, T.;

Precision Electromagnetic Measurements, 1988. CPEM 88 Digest. 1988 Confe on , June 7-10, 1988

Pages: 357 - 357

[Abstract] [PDF Full-Text (356KB)] IEEE CNF

#### 45 Broadcast camera using digital signal processing

Asada, R.; Nishikawa, S.; Toyoda, H.; Miyakawa, Y.; Kitamura, Y.; Watanabe Kiguchi, T.; Taniguchi, M.;

Broadcasting Convention, 1990. IBC 1990., International, 21-25 Sep 1990 Pages: 159 - 163

[Abstract] [PDF Full-Text (264KB)] IEE CNF

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